Model Bug Fixes for BSIM4.2.1

- ❖ 1/f noise model bug fix
- Memory pointer bug
- * ACDE check
- **❖** Temperature parameters for parasitic diodes
- ❖ Bug fix for narrow width effect
- ❖ Addition of Gate Induced Source Leakage
- ❖ L,W,Tox parameter warning limit checking

1/f Noise Model Bug Fix

Requested by David Zweidinger Keith Green Britt Brooks

Texas Instruments

Problem: negative DelClm under certain conditions of voltage bias, temperature, L, and W

$$S_{id,inv}(f) = \frac{k_B T q^2 \mathbf{m}_{eff} I_{ds}}{C_{oxe} L_{eff}^2 A_{bulk} f^{ef} \cdot 10^0} \left(NOIA \log \left(\frac{N_0 + N^*}{N_l + N^*} \right) + NOIB \left(N_0 - N_l \right) + \frac{NOIC}{2} \left(N_0^2 - N_l^2 \right) \right)$$

$$+ \frac{k_B T I_{ds}^2 \Delta L}{C lm} \underbrace{NOIA + NOIB N_l + NOIC N_l^2}_{W_{eff}^2 \cdot L_{eff}^2 f^{ef} \cdot 10^0} \underbrace{NOIA + NOIB N_l + NOIC N_l^2}_{N_l + N^*} \right)$$

$$= Litl \cdot \log \left(\frac{V_{ds} - V_{dseff}}{Litl} + EM \right)$$

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$$= \frac{V_{ds} - V_{dseff}}{Litl} + \frac{V_{ds} - V_{dse$$

DelClm = pParam->BSIM4litl * log (MAX(T0, N_MINLOG));

Memory Pointer Bug

Requested by David Zweidinger Keith Green Britt Brooks

Texas Instruments

Problem: No value assignment to pParam for no-binning approach.

In b4temp.c:

```
while ((pSizeDependParamKnot != NULL) && Size_Not_Found)
{    if ((here->BSIM4l == pSizeDependParamKnot->Length)
        && (here->BSIM4w == pSizeDependParamKnot->Width)
        && (here->BSIM4nf == pSizeDependParamKnot->NFinger))
{        Size_Not_Found = 0;
        here->pParam = pSizeDependParamKnot;
        pParam = here->pParam; /*bug-fix */
    }
}
```

ACDE (capMod 2) Checking

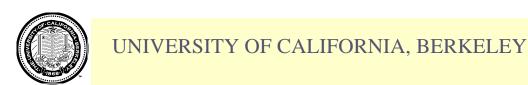
Requested by David Zweidinger Keith Green Britt Brooks

Texas Instruments

Problem: warning message for other capacitance models

In b4check.c:

```
if(model->BSIM4capMod ==2) {
    if (pParam->BSIM4acde < 0.4)
    { fprintf(fplog, "Warning: Acde = %g is too small.\n", pParam->BSIM4acde);
        printf("Warning: Acde = %g is too small.\n", pParam->BSIM4acde);
    }
    if (pParam->BSIM4acde > 1.6)
    { fprintf(fplog, "Warning: Acde = %g is too large.\n", pParam->BSIM4acde);
        printf("Warning: Acde = %g is too large.\n", pParam->BSIM4acde);
    }
}
```



Temperature Parameters for Parasitic Diodes

Requested by Alex Zavorine Circuit Semantics

Jane Xi UC Berkeley

Problems: Model parameters be reassigned with new value for parasitic diode parameters in b4temp.c

In bsim4def.h, new Pre-calculated constants added:

double BSIM4SunitAreaTempJctCap;

double BSIM4DunitAreaTempJctCap;

double BSIM4SunitLengthSidewallTempJctCap;

double BSIM4DunitLengthSidewallTempJctCap;

double BSIM4SunitLengthGateSidewallTempJctCap;

double BSIM4DunitLengthGateSidewallTempJctCap;

Modifications needed in bsim4def.h, b4temp.c, b4ld.c.

Bug Fix for Narrow Width Effect

Requested by Mark Cao Jane Xi UC Berkeley

In b4ld.c:

```
T0 = pParam->BSIM4dvt1w * pParam->BSIM4weff * Leff / ltw;
if (T0 < EXP_THRESHOLD)
{    T1 = exp(T0);
    T2 = T1 - 1.0;
    T3 = T2 * T2;
    T4 = T3 + 2.0 * T1 * MIN_EXP;
    T5 = T1 / T4;
    dT1_dVb = -T0 * T1 * dltw_dVb / ltw; /* bug fix -JX */
    dT5_dVb = dT1_dVb * (T4 - 2.0 * T1 * (T2 + MIN_EXP)) / T4 / T4;
}
```

Addition of GISL(Gate Induced Source Leakage) in BSIM4 (bug fix)

Requested by David Zweidinger Keith Green Britt Brooks
Tom Vrotsos Vinod Gupta John Krick
Texas Instruments

Advantage: an enormous impact on circuit simulation convergence

Follow the same model of I_{GIDL}:

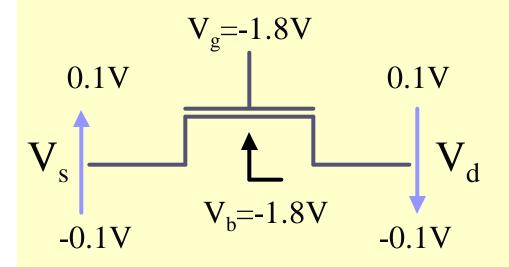
$$I_{GISL} = AGIDL \cdot W_{effCJ} \cdot Nf \cdot \frac{-V_{ds} - V_{gde} - EGIDL}{3 \cdot T_{oxe}} \cdot \exp \left(-\frac{3 \cdot T_{oxe} \cdot BGIDL}{-V_{ds} - V_{gde} - EGIDL} \right) \cdot \frac{V_{sb}^{3}}{CGIDL + V_{sb}^{3}}$$

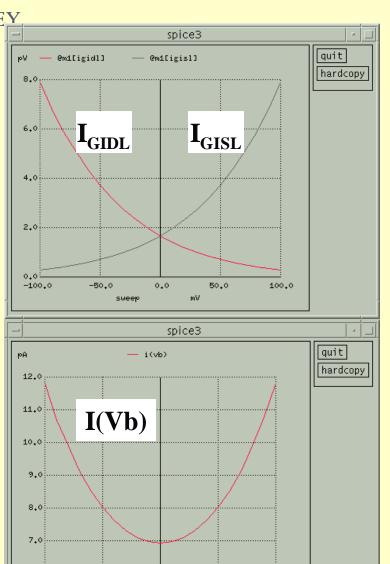
Modifications needed in b4ld.c, b4acld.c, b4pzld.c, b4cvtest.c



UNIVERSITY OF CALIFORNIA, BERKELEY

Gummel's Symmetry Test for GIDL & GISL





50.0

mV

100.0

6.0

-100.0

-50.0

sweep

L,W,Tox Parameter Warning Limit

Requested by David Zweidinger Keith Green Britt Brooks

Texas Instruments

	Original	Now	Recommened
Leff (m)	5e-8	1e-9	1e-8
Leffcv (m)	5e-8	1e-9	1e-8
Weff (m)	1e-7	1e-9	1e-7
Weffcv (m)	1e-7	1e-9	1e-7
Toxe (m)	1e-9	1e-10	5e-10
Toxp (m)	1e-9	1e-10	5e-10
Toxm (m)	1e-9	1e-10	5e-10

- •If(L,W,Tox <=0) {fatal message; Fatal_Flag =1;}
- •If(L,W,Tox < warning limit) {warning messages;}
- •Recommended value here are for a meanful output from BSIM4